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|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/709,844 | BALSDON ET AL. | |
| | | Examiner | Art Unit | Page 1 of 2 |
| | | NAUM B. LEVIN | 2825 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-4,792,913 A | 12-1988 | Buckland et al. | 708/3 |
| * | B | US-5,608,572 A | 03-1997 | Nitta et al. | 359/344 |
| * | C | US-5,796,299 A | 08-1998 | Sei et al. | 327/565 |
| * | D | US-2002/0019713 A1 | 02-2002 | Nagase et al. | 702/66 |
| * | E | US-6,470,479 B1 | 10-2002 | Yamamoto, Shigehisa | 716/4 |
| * | F | US-6,769,103 B2 | 07-2004 | Chevallier et al. | 716/5 |
| * | G | US-6,804,809 B1 | 10-2004 | West et al. | 716/11 |
| * | H | US-6,823,502 B2 | 11-2004 | Wingren et al. | 716/9 |
| * | I | US-6,957,408 B1 | 10-2005 | Teig et al. | 716/12 |
| * | J | US-7,032,199 B2 | 04-2006 | Chevallier et al. | 716/5 |
| * | K | US-7,149,666 B2 | 12-2006 | Tsang et al. | 703/2 |
| * | L | US-7,168,041 B1 | 01-2007 | Durrill et al. | 715/700 |
| * | M | US-7,356,781 B2 | 04-2008 | Koeder et al. | 716/1 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | Adler et al.("A Current Driven Routing and Verification Methodology for Analog Applications", Design Automation Conference, 2000, June 5-9, 2000, page(s):385 – 389. |
| | V | El-Ghazaly et al. "Peak Current and Magnetic Flux Density Variations with Strip Width in Superconducting Microstrip Lines"; BEE MICROWAVE AND GUIDED WAVE LETTERS, VOL. 1, NO. 9, SEPTEMBER 1991. |
| | W | Cong et al., "DUNE—A Multilayer Gridless Routing System"; IEEE TRANSACTIONS ON COMPUTER-AIDED DESIGN OF INTEGRATED CIRCUITS AND SYSTEMS, VOL. 20, NO. 5, MAY 2001. |
| | X | Finch, et al., "A Method for Gridless Routing of Printed Circuit Boards"; Design Automation, 1985. 22nd Conference on 23-26 June 1985 Page(s):509 - 515. |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

| | | | | |
|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination 10/709,844 BALSDON ET AL. | |
| | | Examiner | Art Unit NAUM B. LEVIN 2825 | Page 2 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------|----------------|
| | A | US- | | | |
| | B | US- | | | |
| | C | US- | | | |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
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| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | van Ginneken et al.; "GRIDLESS ROUTING OF GENERAL FLOOR PLANS"; Eindhoven University of Technology Dept. of Electrical Engineering, Automatic System Design Group; 1987, EEE |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.